Approval Sheet

Customer	
Product Number	M0SB-12PB6C03-J
Module speed	PC-133
Pin	144 Pin
CAS Latency	CL-3
SDRAM Operating Temp.	0 °C ~ 70 °C
Date	2 nd November 2023

The Total Solution For Industrial Flash Storage

1. Features

Key Parameter

Industry	Speed	D	tRCD	tRP	tRC		
Nomenclature	Grade	CL=2	CL=2.5	CL=3	(ns)	(ns)	(ns)
PC-133	В	100	-	133	20	20	65

- Single Pulsed RAS- interface
- Fully Synchronous to positive CLK edge
- 4 banks controlled by BA0 & BA1
- Multiple Burst Read with single write option
- Automatic and controlled precharge command
- Auto refresh (CBR) and Self-Refresh
- Standard 144-pin Memory Module
- Intend for 133 MHz applications
- Inputs and Outputs are LVTTL compatible
- VDD=VDDQ= 3.3 Volt \pm 0.3

- Serial Presence Detect with EEPROM
- SDRAM Operation Temperature (Note 1)

0°C ≤ TA ≤ +70°C

- Programmable Device Operation:
 - Burst Type: Sequential or Interleave
 - Device CAS# Latency:2, 3
- RoHS Compliant (Section 14)

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Note: 1. The refresh rate is required to double when TA Exceeds70°C.



2. SDRAM Environmental Requirements

SDR SDRAMs are intended for use in standard office environments that have limited capacity

for heating and air conditioning.

Symbol	Parameter	Rating	Units	Notes			
TOPR	Operating Temperature (ambient)	0 to +70	°C	1			
Тѕтс	Storage Temperature	-55 to +150	°C				
1. The component maximum case temperature (Tcase) shall not exceed the value specified in the SDR DRAM component specification.							



3. Ordering Information

SDR SODIMM								
Part Number	Density	Speed	DIMM	Number of	Number of	ECC		
			Organization	DRAM	rank	ECC		
M0SB-12PB6C03-J	512MB	PC-133	64Mx64	8	2	N		

4. Pin Configurations (Front side/Back side)

Pin	Front	Pin	Back	Pin	Front	Pin	Back	Pin	Front	Pin	Back
1	VSS	2	VSS	51	DQM14	52	DQM46	95	DQ21	96	DQ53
3	DQ0	4	DQ32	53	DQM15	54	DQM47	97	DQ22	98	DQ54
5	DQ1	6	DQ33	55	Vss	56	Vss	99	DQ23	100	DQ55
7	DQ2	8	DQ34	57	NC	58	NC	101	VDD	102	VDD
9	DQ3	10	DQ35	59	NC	60	NC	103	A6	104	A7
11	VDD	12	VDD		2396 - 2012 -	1		105	A8	106	BAO
13	DQ4	14	DQ36		Volta	ge Key		107	VSS	108	VSS
15	DQ5	16	DQ37					109	A9	110	BA1
17	DQ6	18	DQ38	61	**CLK0	62	**CKED	111	A10/AP	112	A11
19	DQ7	20	DQ39	63	VDD	64	VDD	113	VDD	114	VDD
21	Vss	22	Vss	65		66	VDD CAS	115	DQM2	116	DQM6
23	DQM0	24	DQM4	67	WE	68	**CKE1	117	DQM3	118	DQM7
25	DQM1	26	DQM5	69	**CSD	70	A12	119	VSS	120	Vss
27	VDD	28	VDD	71	**CS1	72	*A13	121	DQ24	122	DQ56
29	AD	30	A3	73	DU	74	**CLK1	123	DQ25	124	DQ57
31	A1	32	A4	75	VSS	76	Vss	125	DQ26	126	DQ58
33	A2	34	A5	77	NC	78	NC	127	DQ27	128	DQ59
35	Vss	36	VSS	79	NC	80	NC	129	VDD	130	VDD
37	DQ8	38	DQ40	81	VDD	82	VDD	131	DQ28	132	DQ60
39	DQ9	40	DQ41	83	DQ16	84	DQ48	133	DQ29	134	DQ61
41	DQ10	42	DQ42	85	DQ17	86	DQ49	135	DQ30	136	DQ62
43	DQ11	44	DQ43	87	DQ18	88	DQ50	137	DQ31	138	DQ63
45	VDD	46	VDD	89	DQ19	90	DQ51	139	VSS	140	VSS
47	DQ12	48	DQ44	91	VSS	92	VSS	141	SDA	142	SCL
49	DQ13	50	DQ45	93	DQ20	94	DQ52	143	VDD	144	VDD

5. Architecture

Pin Definition

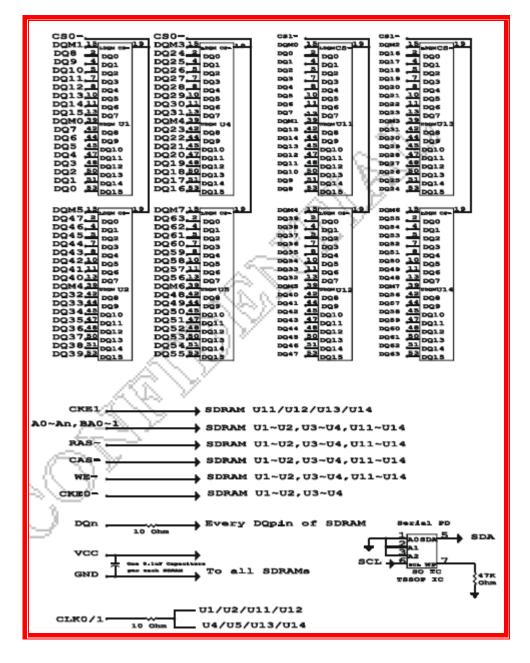
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Pin Name	Description	Pin Name	Description
A0 - A12	SDRAM address bus	CKE0 – CKE1	SDRAM clock enable lines
SA0 - SA1	SDRAM Bank Address Inputs	SCL	Serial Presence Detect Clock Input
RAS-	SDRAM row address strobe	SDA	Serial Presence Detect Data input/output
CAS-	SDRAM column address strobe	DQM0 – DQM7	SDRAM data masks
WE-	SDRAM write enable	Vdd	Power Supply
CS0 CS1-	Chip select input	GND	Ground
CLK0 – CLK1	SDRAM Clock input.	DU	Spare Pin
D0 – D63	DIMM memory data bus	NC	No connection



6. Function Block Diagram:

- (512MB, 2 Ranks, 32Mx16 SDR SDRAMs)



7. Absolute Maximum Ratings

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Parameter	Rating	Units			
Storage Temperature	-55 to 150	°C			
Input/output voltage	-0.3 to VDD	V			
Power supply voltage	-0.3 to +4.6	V			
Note: Stresses greater than those listed under "Absolute Maxim	um Ratings" may cause permanent dama	age to the			
device. This is stress rating only, and functional operation of the device at these or any other conditions above those					
indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating					

conditions for extended periods may affect reliability.

8. DC Operating Conditions

- DC Electrical Operating Conditions

Symbol	Parameter	Min	Тур.	Мах	Units	Notes	
Vdd	Supply Voltage	3.0	3.3	3.6	V		
VDDQ	Supply Voltage	3.0	3.3	3.6	V		
VIH (DC)	Input High (Logic1) Voltage	2.0	-	Vcc + 0.3	V	1,2	
VIL (DC)	Input Low (Logic0) Voltage	-0.3	-	0.8	V	1,2	
Note:							
1. All voltages referenced to Vss							
2. VIH may overshoot to VCC + 2.0 V for pulse width of < 4ns with 3.3V. VIL may undershoot to -2.0 V for pulse							

width < 4.0 ns with 3.3V. Pulse width measured at 50% points with amplitude measured peak to DC reference.

- DC Electrical Characteristics

Symbol	Parameter	Min	Мах	Units
lı(L)	Input Leakage Current, any input (0.0V \leq VIN \leq VDD), All Other Pins Not Under Test = 0V	-2	2	μA
IO(L)	Output Leakage Current (Do∪⊤ is disabled, 0.0V ≤ Vo∪⊤ ≤ VɒDQ)	-2	2	μA
Vон	Output Level (LVTTL) Output "H" Level Voltage (IOUT = -2.0mA)	2.4	-	V
Vol	Output Level (LVTTL) Output "L" Level Voltage (IOUT = +2.0mA)	-	0.4	V



9. Capacitance

*Note: Capacitance is sampled and not 100% tested.

Symbol	Parameter	Min.	Max.	Units
Ссік	Input Capacitance: CLK	4.5	6	pF
Сім	Input Capacitance: All other input pins and balls	2.5	6	pF
Сю	Input/Output Capacitance: DQ	4	6	pF

10. Operating, Standby, and Refresh Currents

- 512MB SODIMM (2 Ranks, 32Mx16 SDR SDRAMs)

Symbol	Parameter/Condition	PC-133	Unit
I CC1	Operation Current: Burst length = 4, CL = 3, tRC > = $tRC(min)$, tCK > = $tCK(min)$, IO = 0 mA, 2 Bank Interleave Operation	1480	mA
I CC2P	Precharged Standby Current in Power Down Mode: CKE< = VIL(max), tCK> = tCK(min)	56	mA
I CC2N	Precharged Standby Current in Non-Power Down Mode: CKE> = VIH(min), tCK> = tCK(min), Input changed once in 3 cycles.	464	mA
I ссзи	Active Standby Current in Non-Power Down Mode: CKE> = VIH(min), tCK> = tCK(min), Input changed one time	600	mA
І ССЗР	Active Standby Current in Power Down Mode: CKE< = VIL(max), tCK> = tCK(min)	256	mA
I CC4	Burst Operating Current: Burst length = Full Page, tRC = Infinite, CL = 3, tCK> = tCK(min), IO = 0 mA 2 Banks Activated	1240	mA
I CC5	Auto Refresh Current: tRC>= tRC(min)	2160	mA
I CC6	Self Refresh Current: CKE = <0.2 V	56	mA
1. Curren	ts given are valid for a single device		
2. These	parameters depend on the cycle rate and are measured with the cycle determined by the minimum v	alue of tcк a	nd t _{RC} .
Input sigr	als are changed up to three times during tRc(min).		
3. The sp	ecified values are obtained with the output open.		
	ignals are changed once during tcк(min).		
	ignals are changed once during three clock cycles.		
	Standby Current will be higher if Clock Suspend is entered during a burst read cycle (add 1mA per D	Q).	
7. Input s	ignals are stable.		

11. AC Timing Specifications

Complexed	Deservation	PC	·133	Unit				
Symbol	Parameter	Min.	Max.					
Clock an	Clock and Clock Enable							
tAc	DQ output access time from CK/CK#	-	5.4	ns				
tCH	CK high-level width	2.5	-	ns				
tCL	CK low-level width	2.5	-	ns				
tСK	Clock frequency		133	MHz				
tСK	Clock Cycle Time	7		ns				
tτ	Transition time (rise and fall)	0.3	1.5-	ns				
Setup an	d Hold Times							
tis	input setup time	1.5	-	ns				
tін	input hold time	0.8	-	ns				
tcks	CKE Setup Time	1.5		ns				
tckh	CKE Hold Time	0.8		ns				
tmrd	Mode Register Set Command Cycle Time	2		ns				
tsb	Power Down Mode Entry Time	0	7	CLK				
tds	Data-in Setup Time	1.5		ns				
tdh	Data-in Hold Time	0.8		ns				
Comman	d Parameters							
tRCD	/RAS to /CAS delay	15	-	ns				
tRC	Cycle Time	65	-	ns				
tRAS	Active command Period	45	100K	ns				
tRP	Precharge Time	15	-	ns				
tRRD	Bank to Bank delay time	15	-	ns				
tCCD	/CAS to /CAS delay time (same bank)	1	-	CLK				
tdpl	Data-in to Precharge Command for Manual precharge	2		CLK				
Refresh (Cycle							

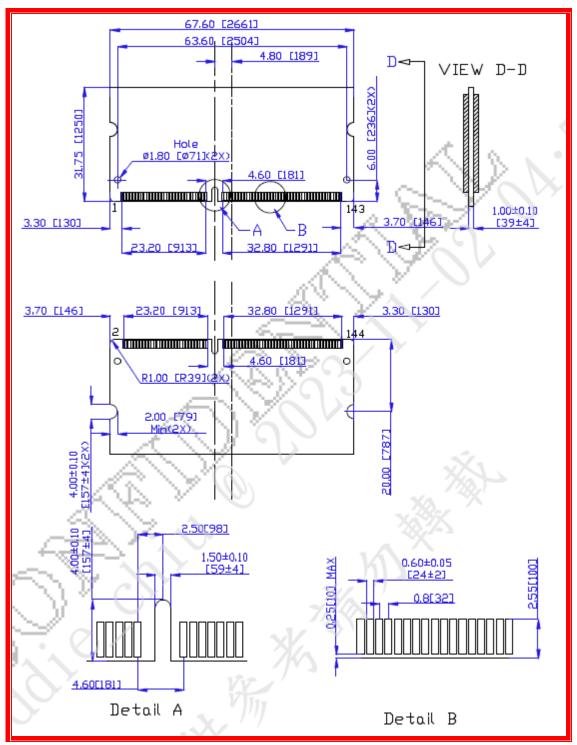
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txsr	Self Refresh Exit to Active Time 1+ tRC -						
tREF	Refresh Period (8192 cycles)	-	64	ms			
Read Cycle							
tOH	Data Out Hold Time 2.5 -		-	ns			
tLZ	Data Out to Low Impedance Time 1 -		Ns				
tHZ	Data Out to High Impedance Time 3 7		7	ns			
tDQZ	DQM Data Out Disable Latency	-	2	CLK			
Write Cycle							
tWR	Write Recovery Time for Auto precharge 2		-	CLK			
tDQW	DQM Write Mask Latency 0 -		-	CLK			



12. PACKAGE DIMENSION

- (512M, 2 Ranks, 32Mx16 SDR SDRAMs)



Note: All dimensions are in millimeters and should be kept within a tolerance of ± 1.27 mm, unless otherwise specified.

13. RoHS Declaration

Innodisk Corporation Tel:(02)7703-3000 Fax:(02) 7703-3555 Internet: http://www.inn 战宣告書(RoHS Declaration of Conformity) duct: All Innodisk EM Flash and Dram proc	odisk.co
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Revision Log

Rev	Date	Modification
0.1	3 rd March 2015	Preliminary Edition
1.0	3 rd March 2015	Official Release.
1.1	14 th June 2018	Modified based on PCN change PCB.
1.2	2 nd November 2023	Updated 12. PACKAGE DIMENSION